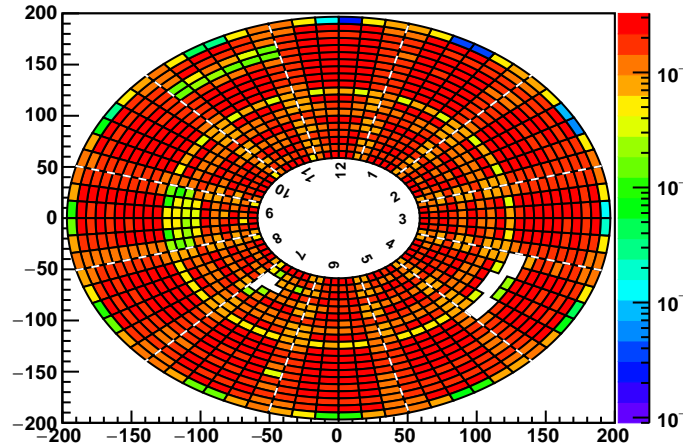
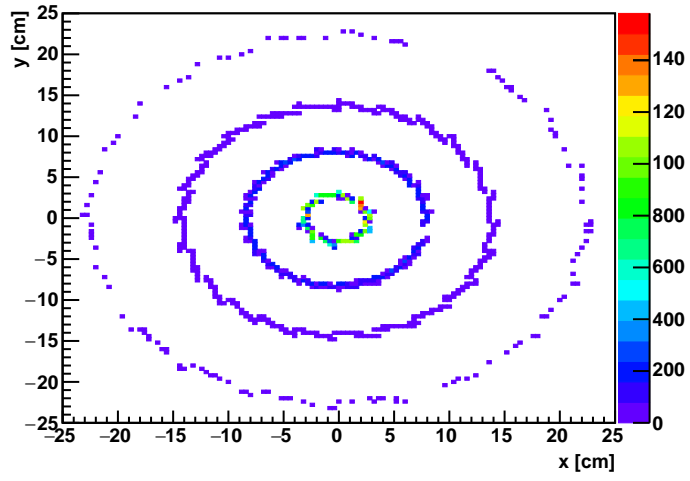


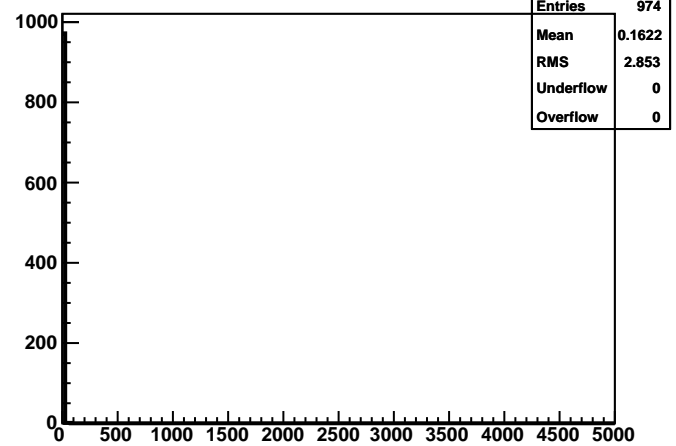
StE point: r-phi distribution of charge, tpcE



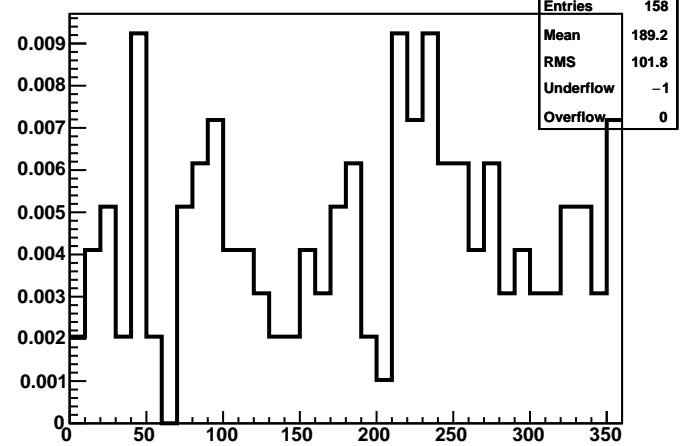
PIXEL, IST, SSD: Distribution of hits in XY



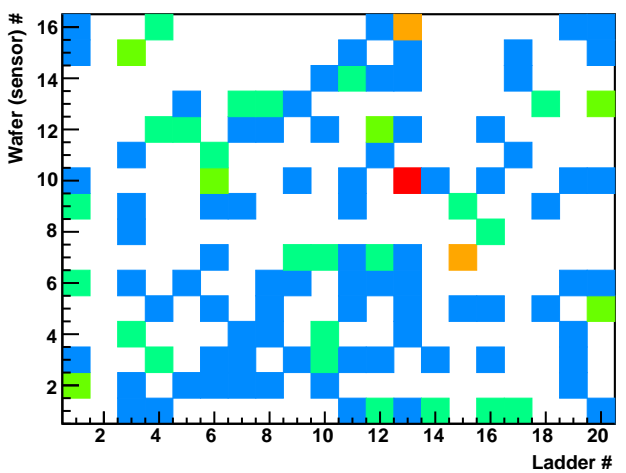
StE point: # hits sst



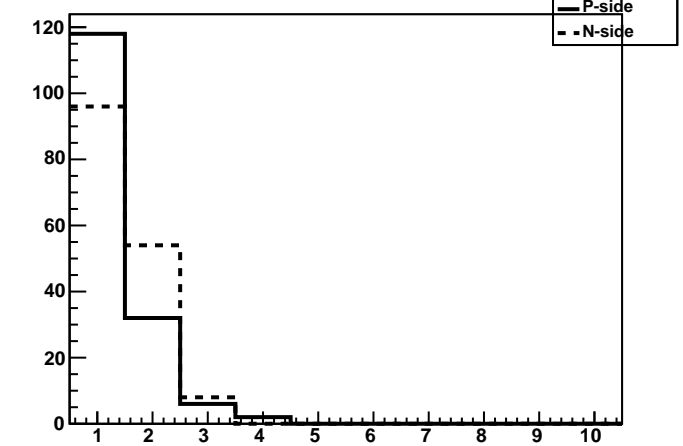
StE SST: ϕ of hits (per event)



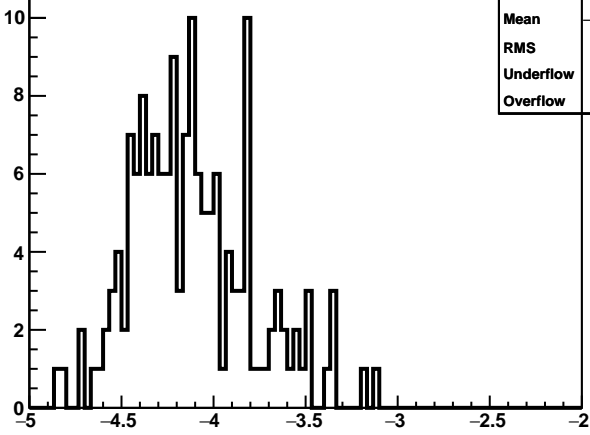
StE SST: wafer id vs ladder id (per event)



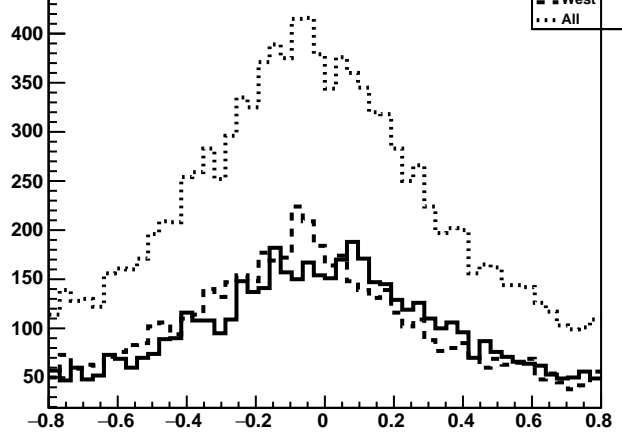
StE SST: size of clusters



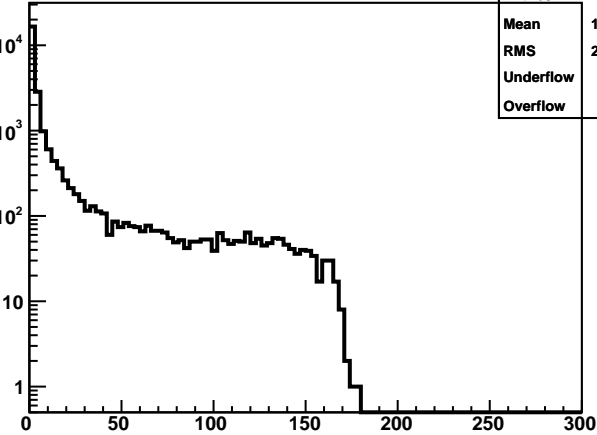
StE SST: log10(energy) of hits



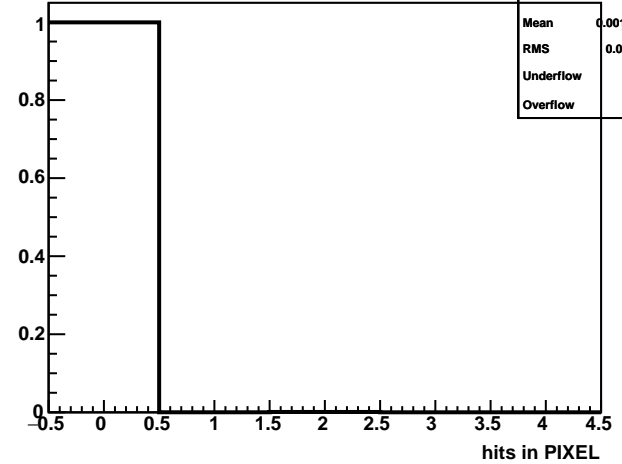
StE globtrk: signed impact param from prim vtx, tpc



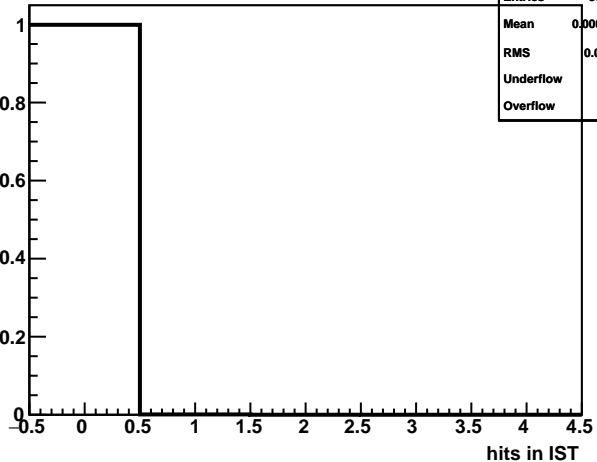
StE globtrk: impact param from prim vtx, tpc



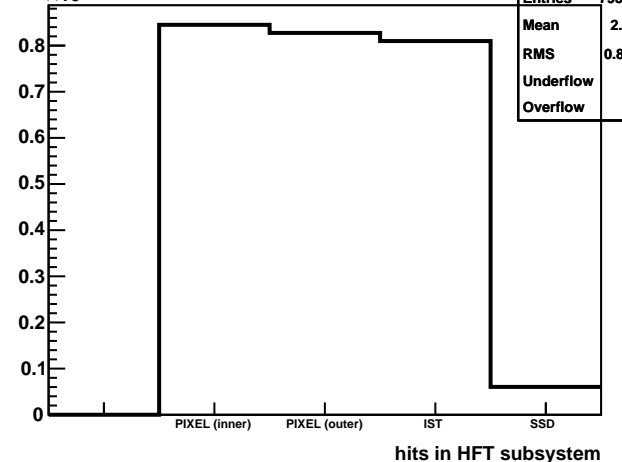
StE PIXEL: Hits per global track



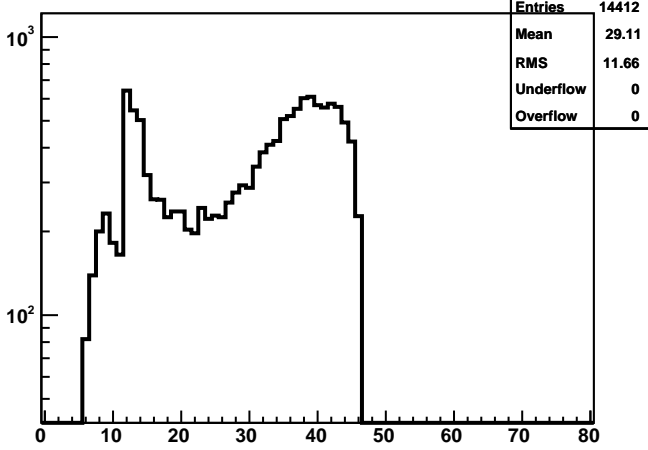
StE IST: Hits per global track



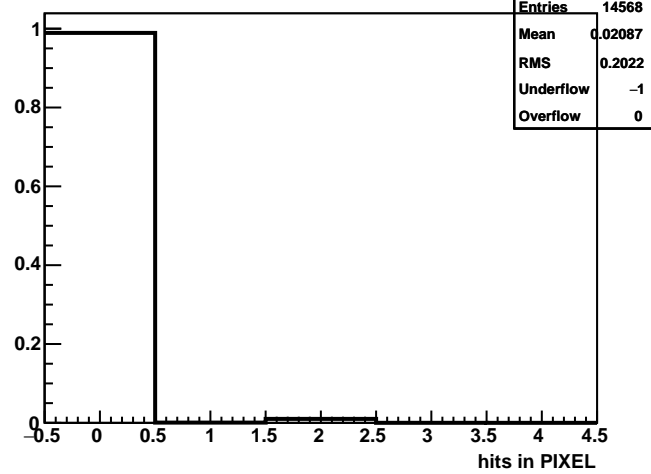
StE HFT: Hits per global track



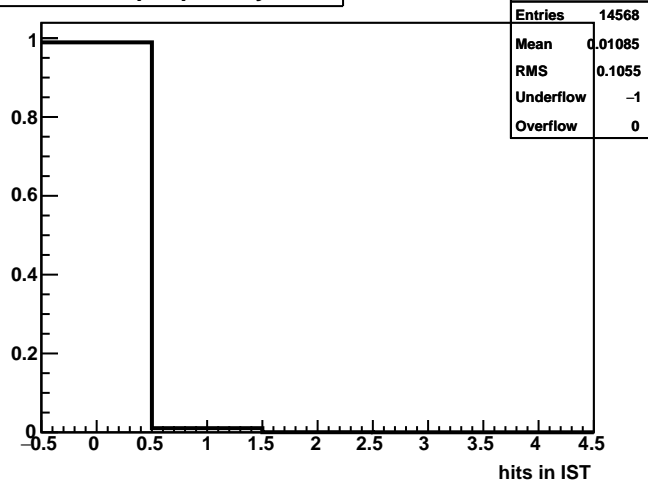
StE primtrk: N fit pnts on trk, tpc



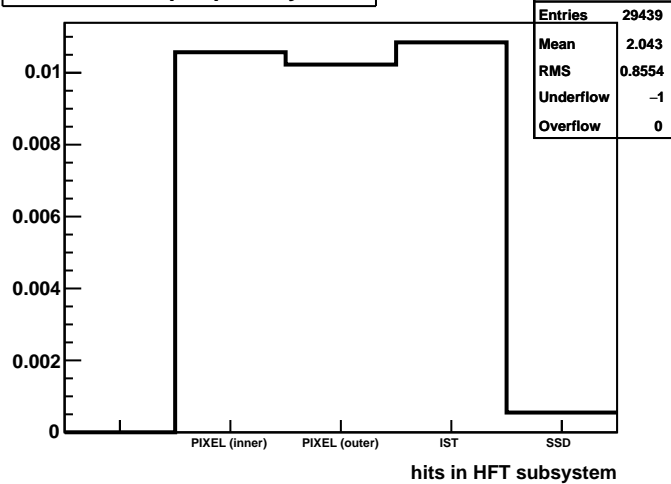
StE PIXEL: Hits per primary track



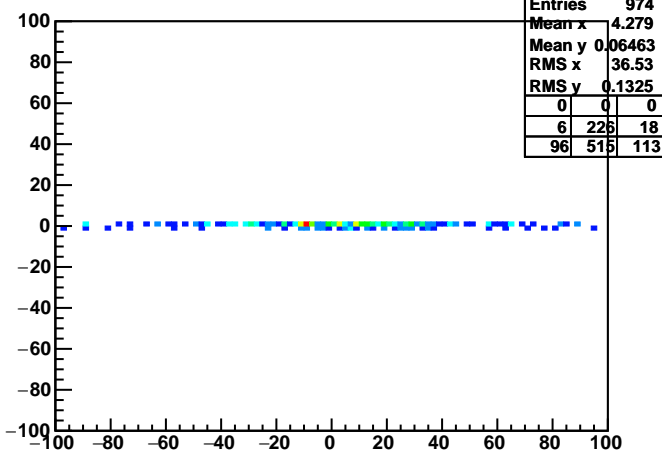
StE IST: Hits per primary track



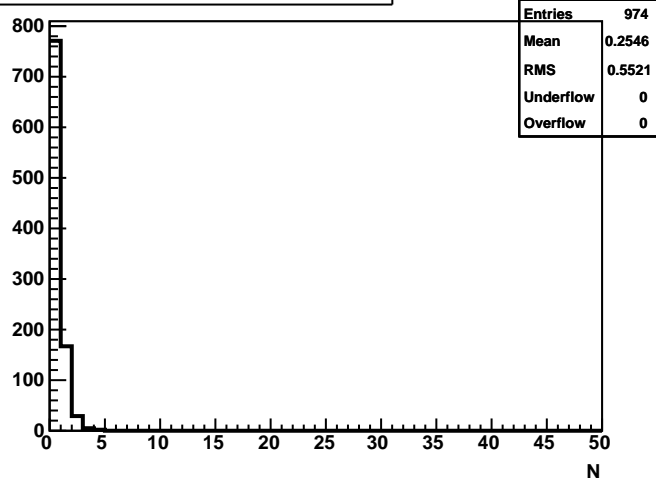
StE HFT: Hits per primary track

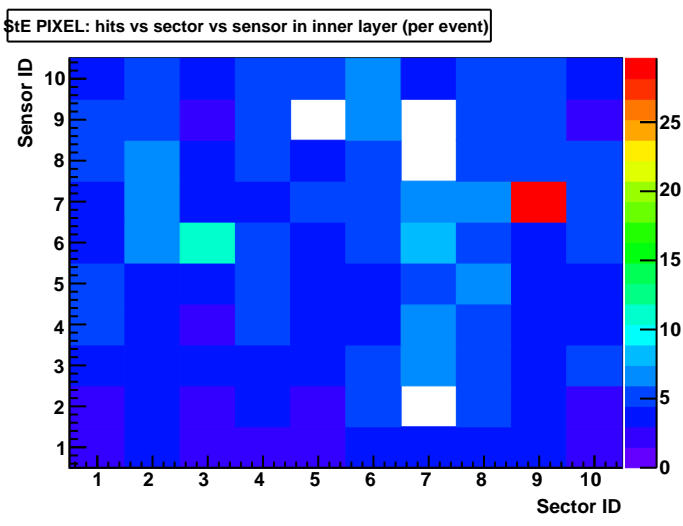
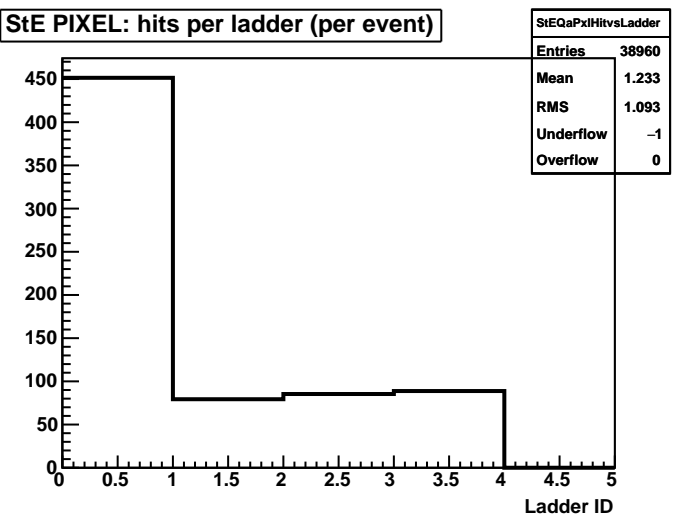
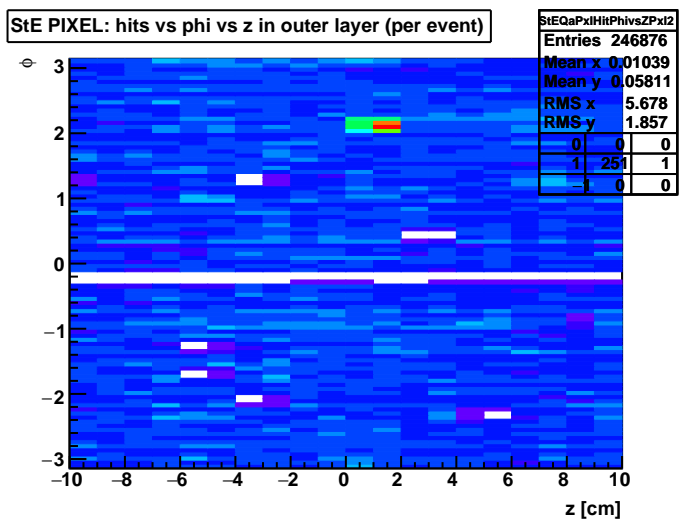
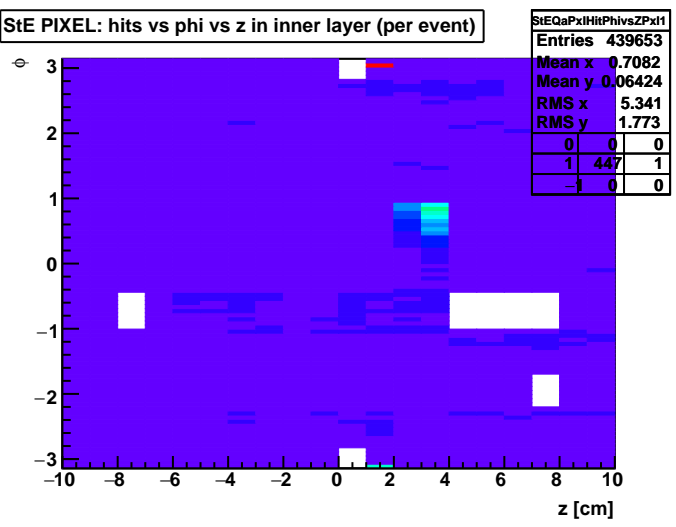
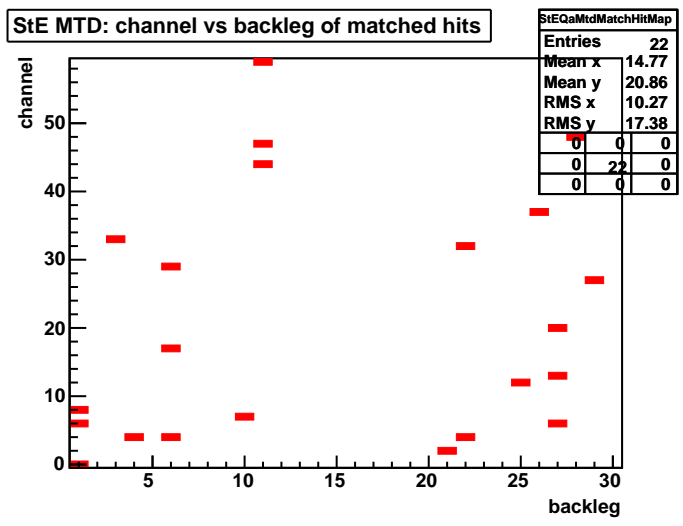
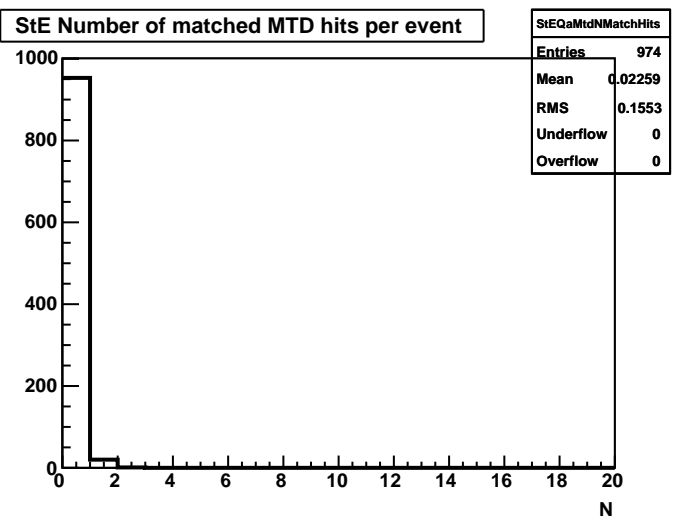


StE VPD vtxz vs TPC vtxz

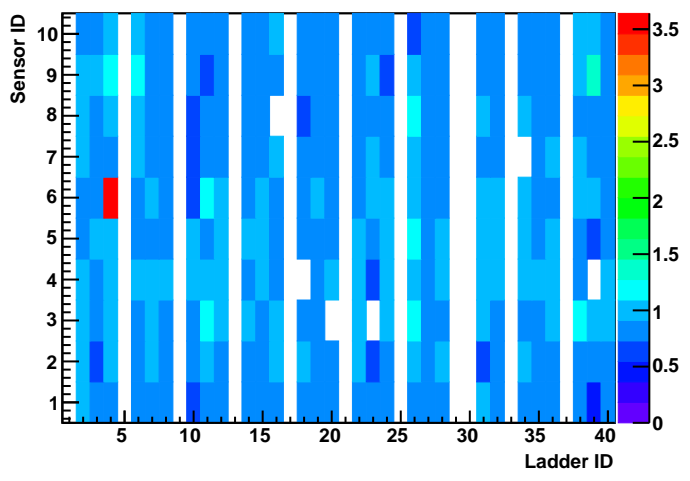


StE Number of MTD hits per event

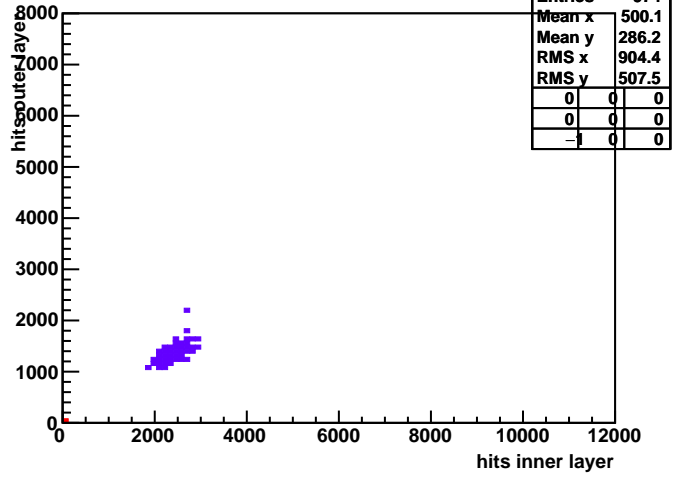




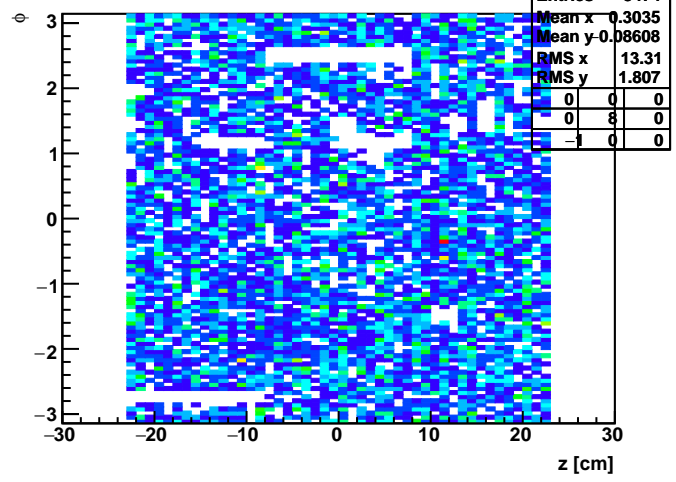
StE PIXEL: hits vs ladder vs sensor in outer layer (per event)



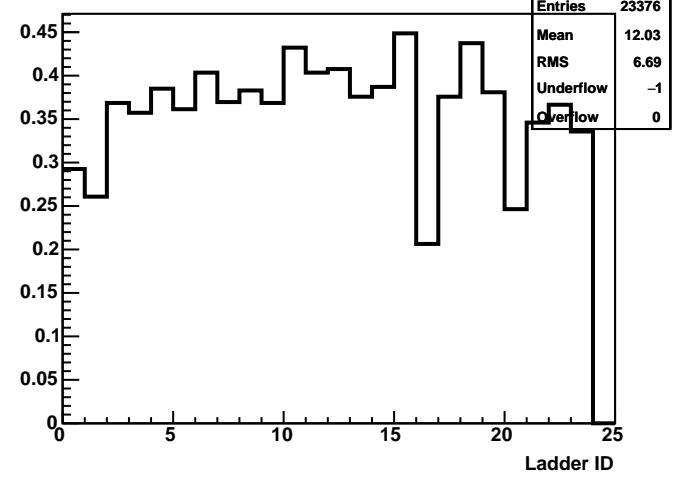
StE PIXEL: Hits in inner vs outer layer (per event)



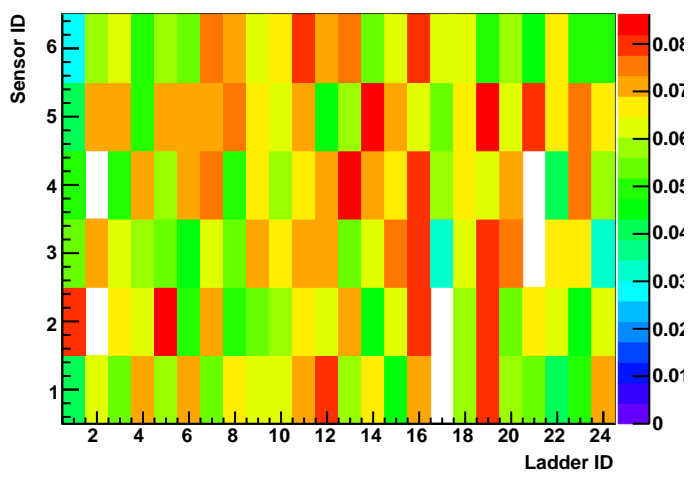
StE IST: Hits vs phi vs z (per event)



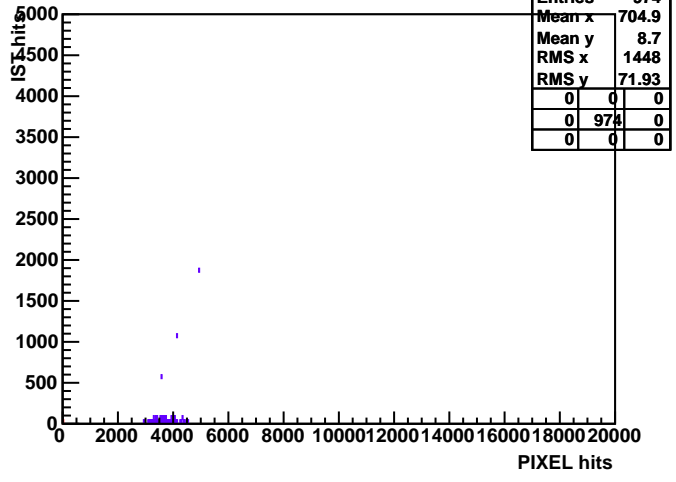
StE IST: Hits per ladder (per event)



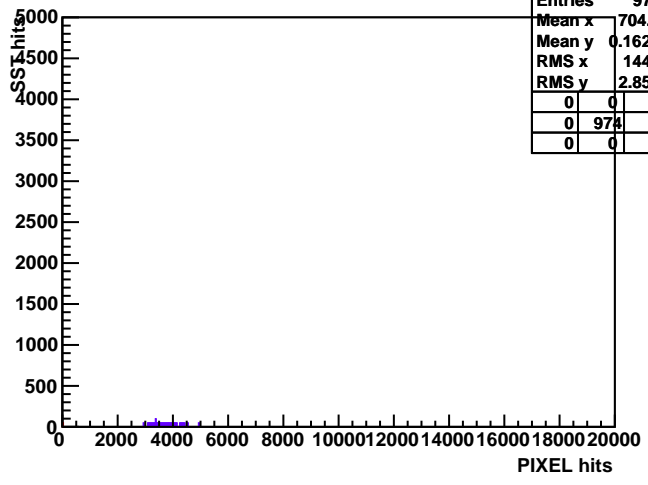
StE IST: Hits vs ladder vs sensor (per event)



StE PIXEL hits vs IST hits



StE PIXEL hits vs SST hits



StE IST hits vs SST hits

